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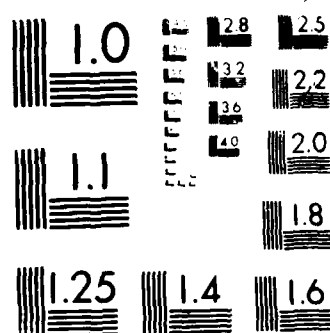
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CENTER FOR RELIABLE COMPUTING  
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### ABSTRACT

This report is a bibliography of the 1986 CRC Publications.

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## LIST OF PUBLICATIONS

### Conference Papers

- [Amer 86a] Amer, H.H., and E.J. McCluskey, "Calculation of the Coverage Parameter for the Reliability Modeling of Fault-Tolerant Computer Systems," *ISCAS'86*, pp.1050-1053. (CRC TR 86-1)
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- 86-17 Wang, L.-T., and E.J. McCluskey, "Complete Feedback Shift Register Design for Built-In Self-Test."
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- Wang, L.T., "Circuits for Pseudo-Exhaustive Test Pattern Generation," *IEEE Workshop on Design for Testability*, Vail, CO, 4/29/86.
- David, R., "The Length of Random Testing of RAMs," *IEEE Workshop on Design for Testability*, Vail, CO, 4/29/86.
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- Amer, H., "Calculation of the Coverage Parameters for the Reliability Modeling of Fault-Tolerant Computer Systems," *International Symposium on Circuits & Systems*, San Jose, CA, 5/5/86.
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- Wang, L.T., and E.J. McCluskey, "Circuits for Pseudo-Exhaustive Test Pattern Generation," *ITC'86*, Washington D.C., 9/11/86.
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- Wang, L.T., and E.J. McCluskey, "Complete Feedback Shift Register Design for Built-In Self-Test," *ICCAD'86*, 11/11/86.

## LIST OF ABBREVIATIONS

*ICCAD'86* = International Conference on Computer-Aided Design, Santa Clara, CA, Nov. 10-13, 1986.

*ISCAS'86* = Proceedings of the International Symposium on Circuits and Systems, San Jose, CA, May 5-7, 1986.

*FJCC* = Proceedings of the Fall Joint Computer Conference, Dallas, TX, Nov. 2-4, 1986.

*ISSCC'86* = Proceedings of the IEEE International Symposium on Circuits and Systems, Anaheim, CA, Feb. 19-21, 1986.

*COMPCON'86* = Computer Society International Conference, San Francisco, CA, March 3, 1986.

*ITC'86* = International Test Conference, Washington, D.C., Sept. 8-11, 1986.

*CICC* = Custom Integrated Circuits Conference, Rochester, NY, May 12-15, 1986.

## 1986 SCHOLARS VISITING CRC

Dr. Peter Gartner, Budapest Polytechnic University, Budapest, Hungary.

Prof. Ren David, Laboratoire d'Automatique de Grenoble, University of Grenoble, France.

Prof. Ramaswami Dandapani, Youngstown State University, Ohio.

Prof. Takashi Nanya, Tokyo Institute of Technology.

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